MTX 3354

MTX Compact

150 MHz - 4 channels

Digital oscilloscope Analyser-Recorder

MTX Oscilloscope-Analyser-Recorder: an essential, original tool!

- 4 complementary instruments for unique compact design and efficiency (oscilloscope / FFT analyser / harmonics analyser / digital recorder)
- Sampling speed up to 100 GS/s and 50 k memory depth per channel in "oscilloscope" mode
- SPO (Smart Persistence Oscilloscope) intelligent display technology
- 4 measurement channels and up to 8 traces on screen
- "Real-time" FFT analyser as standard and math functions on the channels
- Orientable colour LCD screen
- "Windows-like" environment: direct on-screen commands with mouse
- Front panel for frequently-used commands and shortcuts (21 buttons + encoder)
- RS232, Centronics and USB links as standard
- Ethernet network and HTML server as standard

A Brand of CHAUVIN ARNOUX GROUP

MTX 3354: Oscilloscope-Analyser

Technical specifications	MTX 3354
MAN-MACHINE INTERFACE	
Screen specifications	Colour 5"7 LCD (115 x 86 mm) - 320 x 240 resolution + CCFL backlighting
Display mode	8 x 10 divisions - Vectors, Envelope, Averaging
Traces on screen	4 refreshed traces + 4 references
Front panel commands	21 commands + encoder – Direct access & shortcuts – 1 multi-language help key "?"
"On screen" commands	"Windows like" & « on-line user manual » – 100 % commands via mouse
Language choice	From menu, 5 complete languages including English and French
OSCILLOSCOPE MODE	
Vertical deflection	
Bandwidth	150 MHz (20 MHz BWL for 2.5 mV/div)
Channels	4 channels - "class 1"
Inputs impedance	1 MΩ
Maximum permanent input voltage	Cat. II / 300 V – Derating 40 Vpp at 20 MHz
Vertical sensitivity	2.5 mV - 100 V/div + x 10 vertical expansion (maximum sensitivity 250 µV/div)
Vertical accuracy	± 2 %
Vertical zoom	Unique x 10 "Winzoom" - Graphical "1 click" area zooming from mouse or from front panel
Probes factors	Complete physical signal scaling + unit definition ("windows" virtual keyboard)
Horizontal deflection	
Time base speed	From 1 ns up to 200 s/div. – Roll mode from 200 ms to 200 s/div
Horizontal accuracy	± 200 ppm
Horizontal Zoom	YES, up to factor 100 (points actually acquired) - Direct "1-click" area zoom via mouse
Trigger	
Mode	Auto, Normal, Single, Auto 50%
Source	CH1, CH2, CH3, CH4, LINE
Type	Edge, Pulse width or Delay (20/40 ns-10.5 s), Event delay (2-16384), TV line counter (525 = NTSC, 625 = PAL/SECAM), Hold-off (40 ns-10.5 s)
Coupling	AC, DC, LFR, HFR, noise reduction
Sensitivity (CH1 or CH2)	0.6 div up to 1 kHz, trigger level ± 8 div.
Digital memory	
Maximum sampling speed	Repetitive signals = 100 Gs/s – One shot = 200 Ms/s (2 channels), 100 Ms/s (4 channels)
Recording length	From 10 ns to 33 min 20 s
Vertical resolution	9 bits
Noise level	Standard Flash converter (very low noise)
Memory depth	Depth = 50,000 points – up to 16 .trc files of 50 kpts each
"Windows" file system	YES, standard ".cfg", ".trc", ".fct" , "txt", ".bmp", ".gif", ".prn", ".eps" and ".pcl" formats
GLITCH mode	10 ns duration / Time base from 1 µs to 200 s/div (150 MHz bandwidth)
ENVELOPPE mode	YES (displaying 2 x 250 dots on screen)
Average mode	Factors 2, 4, 16 or 64
Digital XY Mode	Between 2 from the 4 curves (calculations possible)
SPO (Smart Persistence Oscilloscope)	
Display mode	1 to 4 channels active simultaneously – "multi-colour" shading or 1 colour per channel
Duration of persistence	100 ms, 200 ms, 500 ms, 1 s, 2 s, 5 s, 10 s and Infinite
Performance	Acquisition speed 50 kwaveforms/s/channel maximum, depending on time base
Other functions	
AUTOSET	Complete + shortcuts "AutoCH1" or "AutoCH2"
FFT Analyser & MATH functions	FFT (2048 samples calculation), + , - , x , / and "User defined complex" math functions
Cursors	3 cursors – V, T, PHASE
Automatic measurements	2 or 18 measurements out of 18 + automatic phase – On all trace types – Cursors and limits
RECORDER MODE (option)	
Acquisition interval	From 40 µs to 54 s acquisition interval
Recording duration	From 2 s up to 31 days
Acquisition modes	Threshold or Window conditions on 4 channels – "Normal 50 k acquisition" or 250 "defaults"
Data analysis	Data time stamping (time & date), complete physical signal scaling and unit definition, cursor measurements and event searching, standard file format for Windows software (".txt")
HARMONICS ANALYSER MODE (option)	
Analysis domain	31-row depth, 1 to 4-channel analysis – fundamental from 40 Hz to 5 kHz
Measurement capabilities	Permanent display: total RMS value & THD – Selected row: %F, phase, freq., Vrms

General specifications	
Set-up memory	"No limitation"
CENTRONICS Printout	Standard / 7 printers modes and "printing in file"
PC communication	Standard RS232C (up to 115.2 kbauds)
USB interface	Standard USB / RS232 (921.6 kbauds), HARD protocol
Ethernet capability	Standard / with integrated HTML server
Mouse interface	Standard / PS2-compatible
Power supply	100-240 V / 47-63 Hz / < 16 W
Environment	Storage -20 °C to +60 °C / operation 0 °C to +40 °C
Casing	Dimensions (W x H x D): 210 x 177 x 200 mm – Weight: 3.3 kg – IP30
Warranty / Origin	3 years / France

State of delivery:
1 oscilloscope, 1 European standard power supply cable, 4 x 1/1 – 1/10 200 MHz probes, 1 PS2 mouse, 1 mouse pad, 1 x 2 m RJ45/RJ45 straight lead, 1 x 2 m RJ45/RJ45 crossed lead, 1 x 1.80 m USB.A/B. lead, 1 CD-ROM containing the operating manual and the programming manual.

MTX3354E-C: colour 150 MHz, 4-channel digital oscilloscope-analyser
MTX3354E-CK: colour 150 MHz, 4-channel digital oscilloscope-analyser + PC Software

CHAUVIN ARNOUX GROUP

FRANCE
Chauvin Arnoux
190, rue Championnet
75876 PARIS Cedex 18
Tel: +33 1 44 85 44 86
Fax : +33 1 46 27 95 59
info@metrix.fr
www.metrix.fr

UNITED KINGDOM
Chauvin Arnoux Ltd
Waldeck House - Waldeck Road
MAIDENHEAD SL6 8BR
Tel: +44 1628 788 888
Fax: +44 1628 628 099
info@chauvin-arnoux.co.uk
www.chauvin-arnoux.co.uk

MIDDLE EAST
Chauvin Arnoux Middle East
P.O. BOX 60-154
1241 2020 JAL EL DIB (BEIRUT)
Tel: +961 1 890 425
Fax: +961 1 890 424
camie@chauvin-arnoux.com
www.chauvin-arnoux.com

Ordering information:

906 201 063 - Ed. 2 - 08/07 - *Specifications subject to change due to technological developments.*